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Bhowmick, S.S.; Madria, S.K.; Wee Keong Ng;

Knowledge and Data Engineering, IEEE Transactions on , Volume: 15 , Issue:

2 , March-April 2003 Pages: 423 - 441

[Abstract] [PDF Full-Text (2779 KB)] IEEE JNL

#### 2 Updating distributed materialized views

Segev, A.; Park, J.;

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[Abstract] [PDF Full-Text (1128 KB)] IEEE JNI

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Cui, Y.; Widom, J.;

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#### 4 Concurrent maintenance of views using multiple versions

Kulkarni, S.; Mohania, M.;

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Pages: 254 - 258

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Segev, A.; Park, J.;

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Chaturvedi, A.R.; Choubey, A.K.; Jinsheng Roan;

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2 Data warehouse clustering on the Web

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de Amo, S.; Alves, M.H.F.;

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